

EMF TEST REPORT
for
BYD Precision Manufacture Co.,Ltd
DELL Venue Cradle
Model No.: K01T, K01T001
Test Model.: K01T

Prepared for : BYD Precision Manufacture Co.,Ltd
No.3001, Baohe Road, Baolong Industrial, Longgang,
Shenzhen,P. R., China

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Report Number : ACS-R14440
Date of Test : Sep.12, 2014
Date of Report : Sep.18, 2014

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REPORT VERIFICATION

Applicant : BYD Precision Manufacture Co.,Ltd

Manufacturer : DELL Inc.

EUT Description : DELL Venue Cradle

(A) MODEL NO. : K01T

(B) POWER SUPPLY : DC 5V

(C) TEST VOLTAGE : DC 5V From Adapter Input AC 120V/60Hz

The device described above is tested by Audix Technology (Shenzhen) Co., Ltd.. The measurement results were contained in this test report and Audix Technology (Shenzhen) Co., Ltd. was assumed full responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT to be technically compliance with the FCC RF Exposure requirements.

This report applies to above tested sample only and shall not be reproduced in part without written approval of Audix Technology (Shenzhen) Co., Ltd..

Date of Test : Sep.12, 2014

Report of date: Sep.18, 2014

Prepared by : Kayli He
Kayli He /Assistant

Reviewed by : Sunny Lu
Sunny Lu / Assistant Manager

Approved & Authorized Signer :



1. GENERAL INFORMATION

1.1. Description of Device (EUT)

EUT name	: DELL Venue Cradle
Model Number	: K01T, K01T001
Test Model	: K01T
Manufacturer	: BYD Precision Manufacture Co.,Ltd No.3001, Baohe Road, Baolong Industrial, Longgang, Shenzhen,P. R., China
Manufacturer	: DELL Inc. One Dell Way, Round Rock, Texas 78682, United States
Date of Test	: Sep.12, 2014
Date of Receipt	: Sep.11, 2014
Sample Type	: Prototype production

1.2. Test Facility

Site Description

Name of Firm : Audix Technology (Shenzhen) Co., Ltd.
No. 6, Ke Feng Rd., 52 Block, Shenzhen
Science & Industrial Park, Nantou, Shenzhen,
Guangdong, China

3m Anechoic Chamber : Certificated by FCC, USA
Registration Number: 90454
Valid Date: Feb.22, 2015

3m & 10m Anechoic Chamber : Certificated by FCC, USA
Registration Number: 794232
Valid Date: Oct.31, 2015

RF Anechoic Chamber : Dimensions are:
[C]10m × [W]5.5m × [H]5m

EMC Lab. : Accredited by DATech, German
Registration Number: DAT-P-091/99-00
Valid Date: Dec.15, 2016

Accredited by NVLAP, USA
NVLAP Code: 200372-0
Valid Date: Mar.31, 2015

1.3. Measurement Uncertainty (95% confidence levels, k=2)

Test Item	Uncertainty
Uncertainty for Radiated Spurious Emission test in RF chamber	3.57dB
Uncertainty for test site temperature and humidity	0.6°C
	3%

2. FCC MPE REQUIREMENT

2.1.GENERAL INFORMATION

For devices designed for typical desktop applications, such a wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 10 cm. E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 10 cm measured from the center of the probe(s) to the edge of the device. Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m.

2.2.LIMIT

Basic Restrictions Reference levels

Basic restrictions for electric, magnetic and electromagnetic fields (0Hz to 300GHz)

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(A) Limits for Occupational/Controlled Exposure				
0.3-3.0	614	1.63	*100	6
3.0-30	1842/f	4.89/f	*900/f ²	6
30-300	61.4	0.163	1.0	6
300-1,500			f/300	6
1,500-100,000			5	6
(B) Limits for General Population/Uncontrolled Exposure				
0.3-1.34	614	1.63	*100	30
1.34-30	824/f	2.19/f	*180/f ²	30
30-300	27.5	0.073	0.2	30
300-1,500			f/1500	30
1,500-100,000			1.0	30

f = frequency in MHz * = Plane-wave equivalent power density

3. ASSESS RESULTS

EUT: DELL Venue Cradle	M/N: K01T
Test Site: Black Yan	Date: 2014-09-12
Temperature : 22.5±0.6 °C Humidity: 53.4±3.0 % Pressure: 101.4±1.0kpa	

B- field strength result (Test frequency range from 10Hz to 400Kh)					
Frequency range	Position	Distance	B-field Strength (uT)(Max)	Limit (uT)	Result
10Hz-400KHz	Front	10cm	0.231	2.3	PASS
	Back	10cm	0.234	2.3	PASS
	Left	10cm	0.235	2.3	PASS
	Right	10cm	0.233	2.3	PASS
	Up	10cm	0.232	2.3	PASS
	Down	10cm	0.234	2.3	PASS
H- field strength result (Test frequency range from 300KHz to 30MHz)					
Frequency range	Position	Distance	H-field Strength (A/m)(Max)	Limit (A/m)	Result
300KHz-30MHz	Front	10cm	0.0196	0.073	PASS
	Back	10cm	0.0183	0.073	PASS
	Left	10cm	0.0097	0.073	PASS
	Right	10cm	0.0171	0.073	PASS
	Up	10cm	0.0156	0.073	PASS
	Down	10cm	0.0147	0.073	PASS

H- field strength result (Test frequency range from 27MHz to 1GHz)					
Frequency range	Position	Distance	H-field Strength (A/m)(Max)	Limit (A/m)	Result
27MHz-1GHz	Front	10cm	0.0085	0.073	PASS
	Back	10cm	0.0080	0.073	PASS
	Left	10cm	0.0081	0.073	PASS
	Right	10cm	0.0089	0.073	PASS
	Up	10cm	0.0063	0.073	PASS
	Down	10cm	0.0076	0.073	PASS
E- field strength result (Test frequency range from 100MHz to 60GHz)					
Frequency range	Position	Distance	Power density (mW/cm2) (Max)	Limit (V/m)	Result
100MHz-60GHz	Front	10cm	0.09	0.2	PASS
	Back	10cm	0.12	0.2	PASS
	Left	10cm	0.08	0.2	PASS
	Right	10cm	0.10	0.2	PASS
	Up	10cm	0.09	0.2	PASS
	Down	10cm	0.08	0.2	PASS

Note1: The assess distance is 10cm.

Note2: The more tighter limit apply to each band.

4. PHOTOGRAPHS



5. PHOTOS OF THE EUT

Figure 1

General Appearance of the EUT

**Figure 2**

General Appearance of the EUT



Figure 3

General Appearance of the EUT

**Figure 4**

General Appearance of the EUT



Figure 5
Inside of the EUT



Figure 6
Inside of the EUT



Figure 7
Inside of the EUT

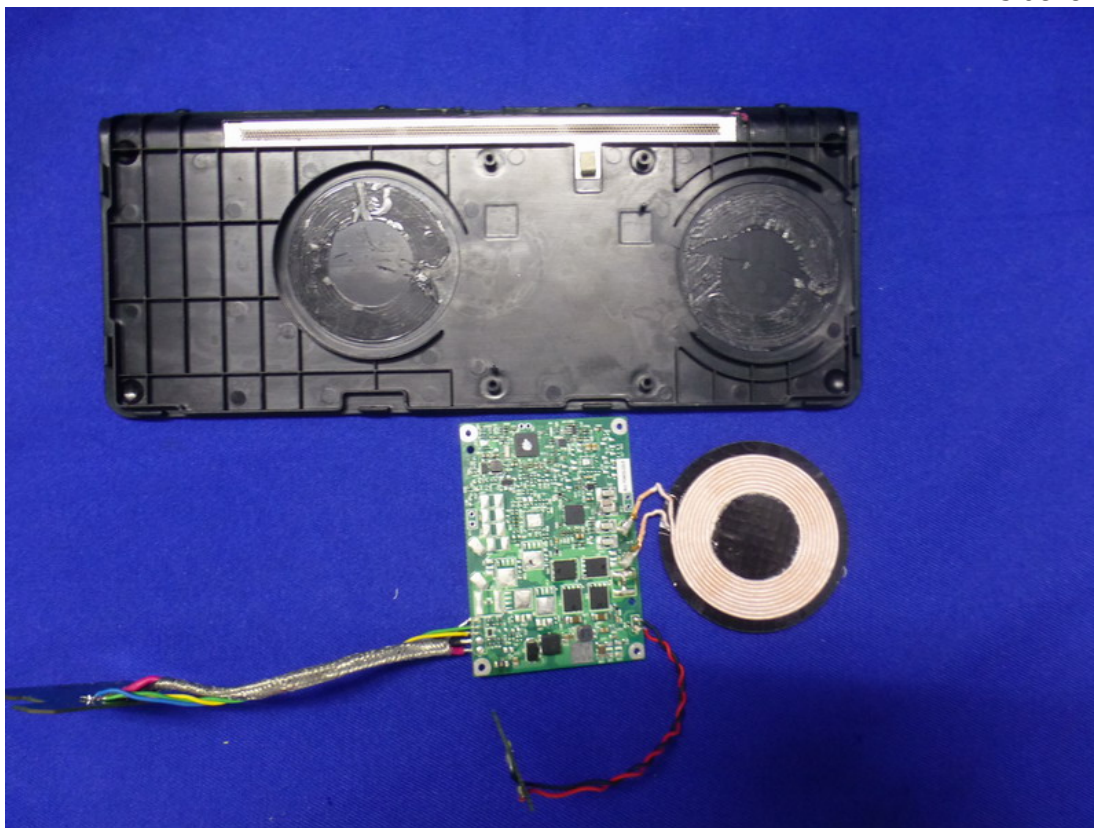


Figure 8
Component side of the PCB

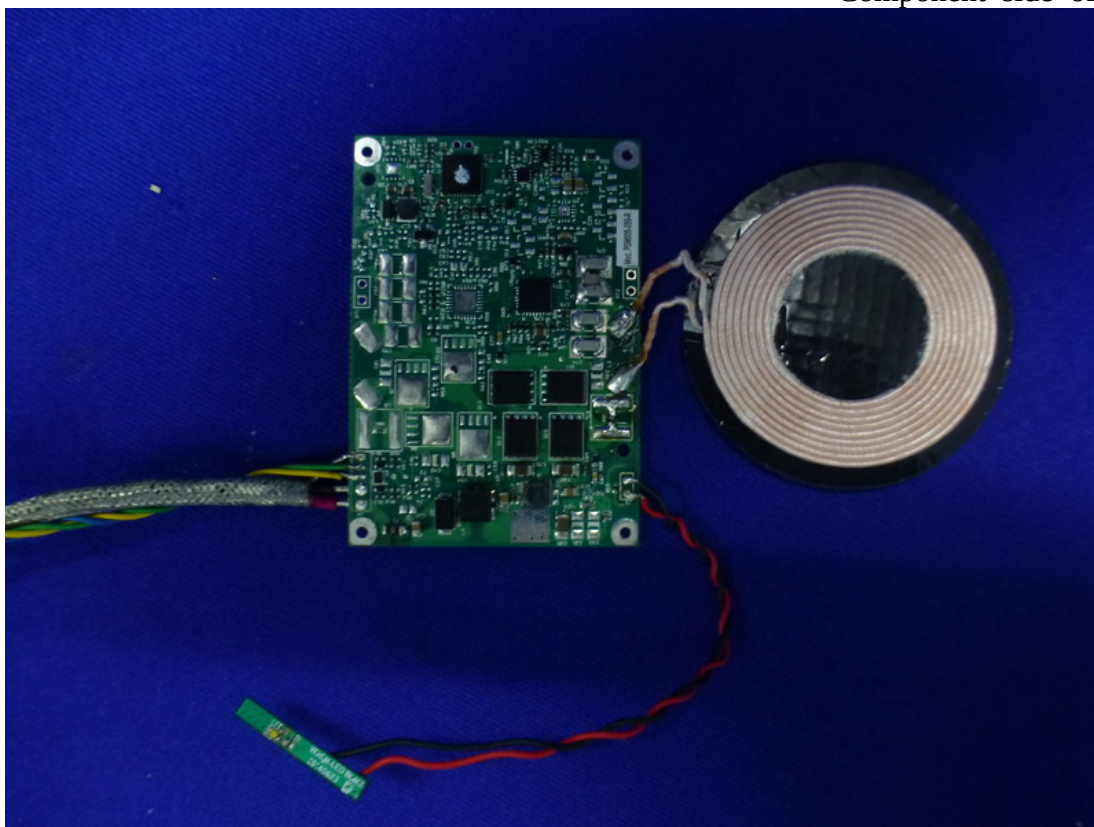


Figure 9
Component side of the PCB

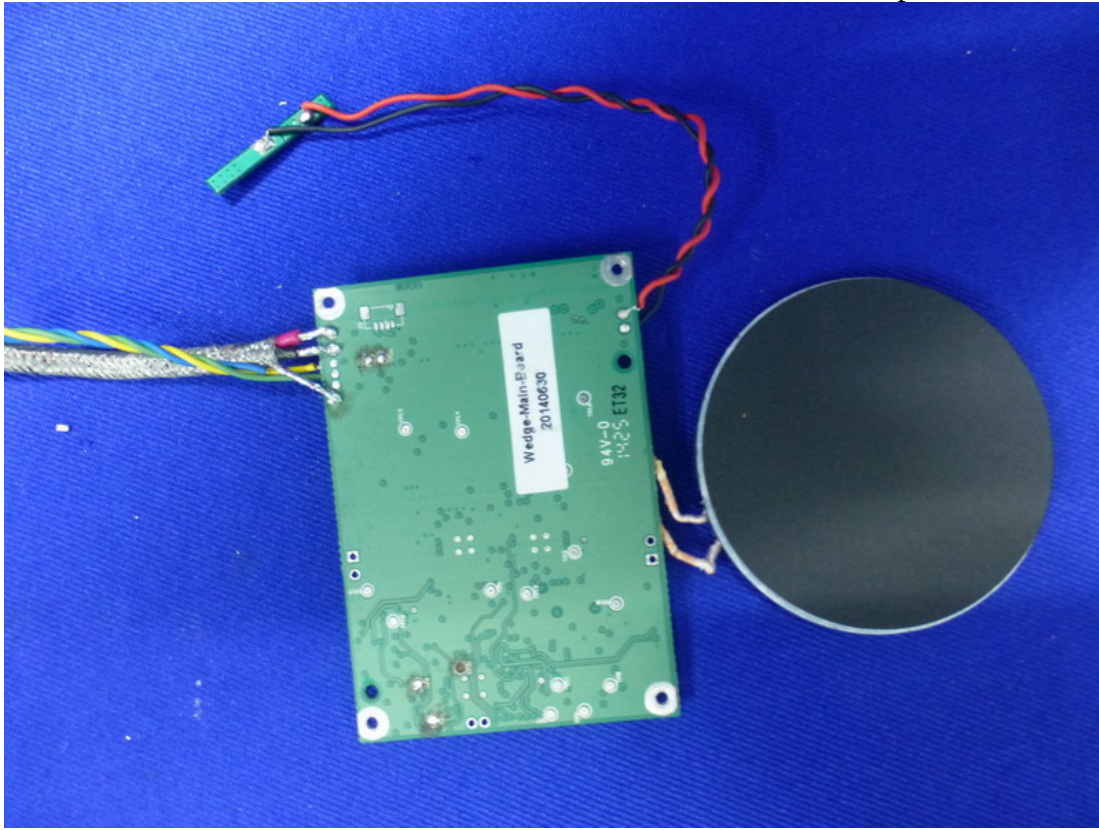


Figure 10
Component side of the PCB

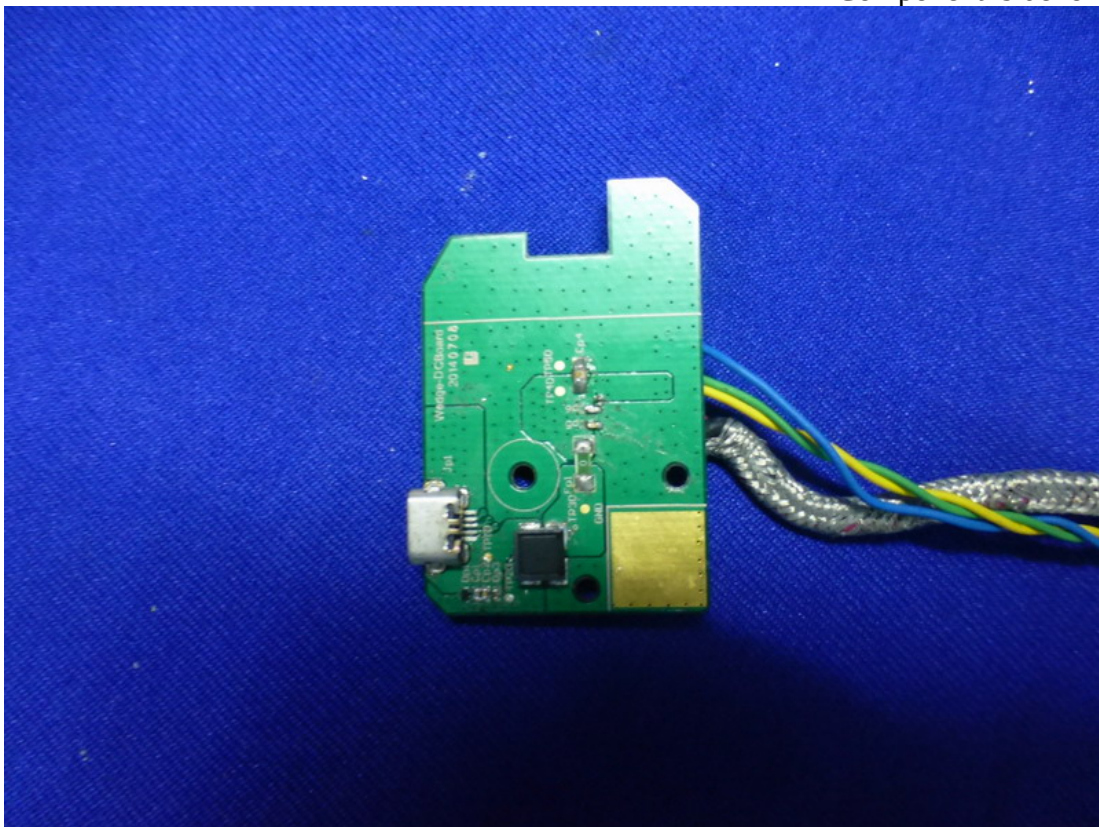


Figure 11
Component side of the PCB

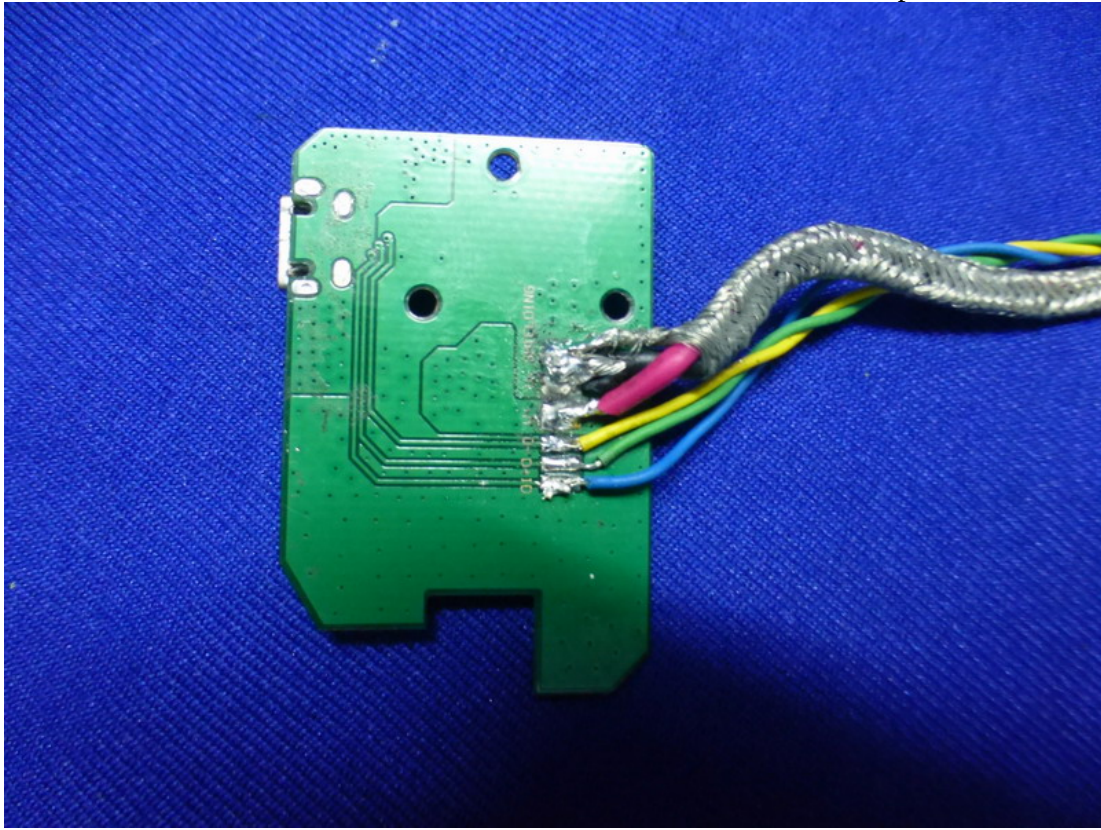


Figure 12
Component side of the PCB

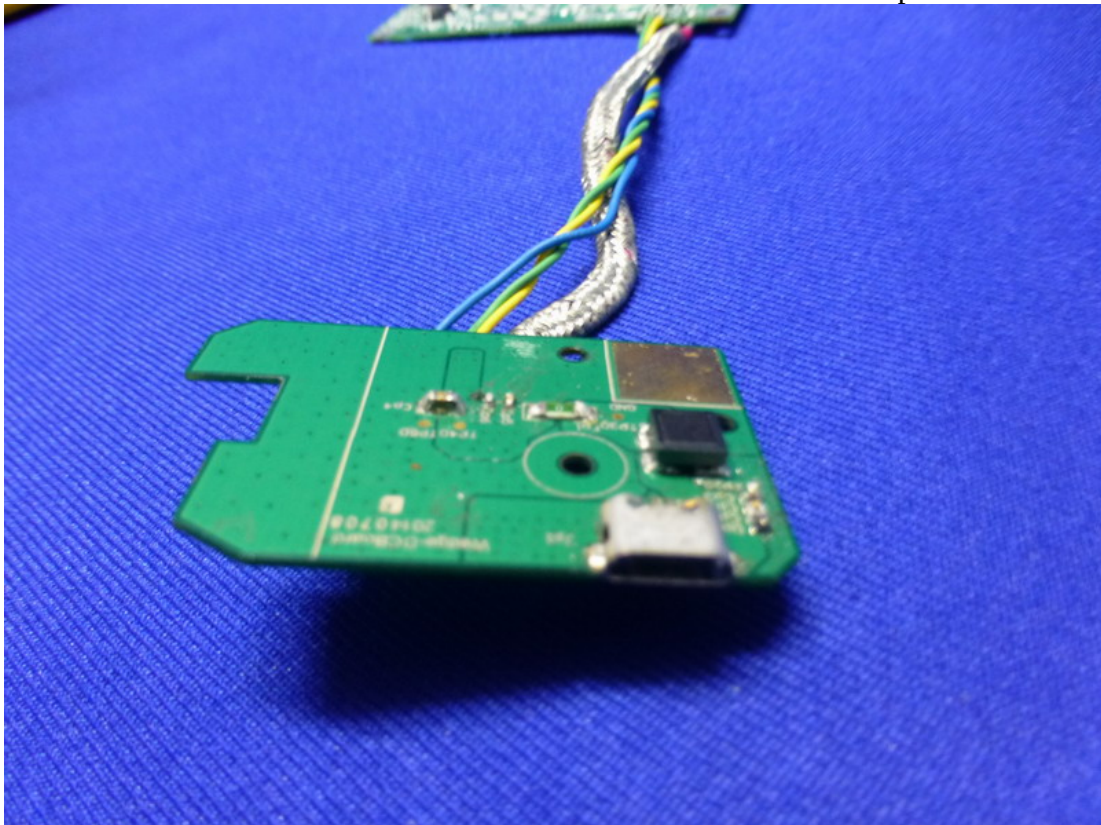


Figure 13
USB Cable**Figure 14**
Adapter of the EUT

Figure 15
Adapter of the EUT



Figure 16
Adapter of the EUT



Figure 17
Adapter of the EUT

